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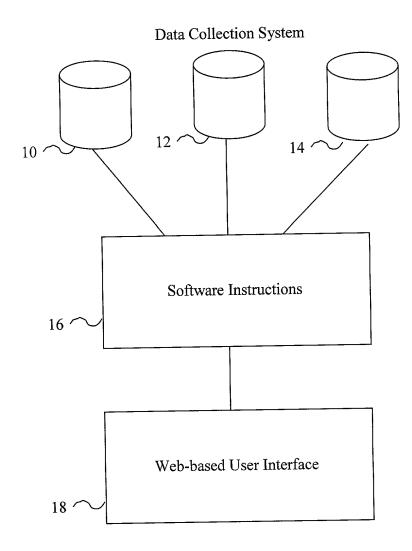


FIG.1

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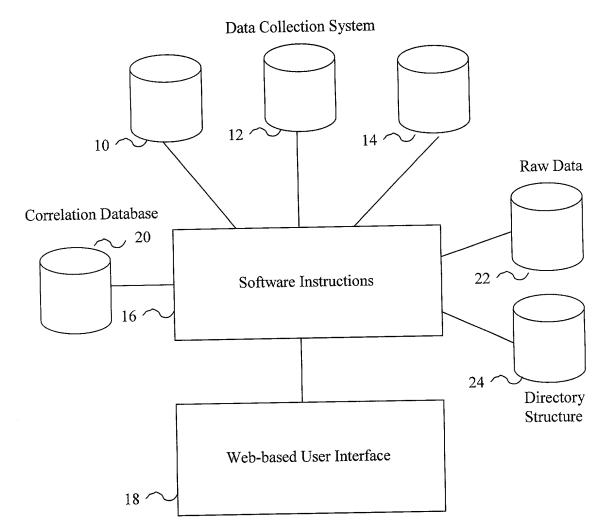


FIG.2

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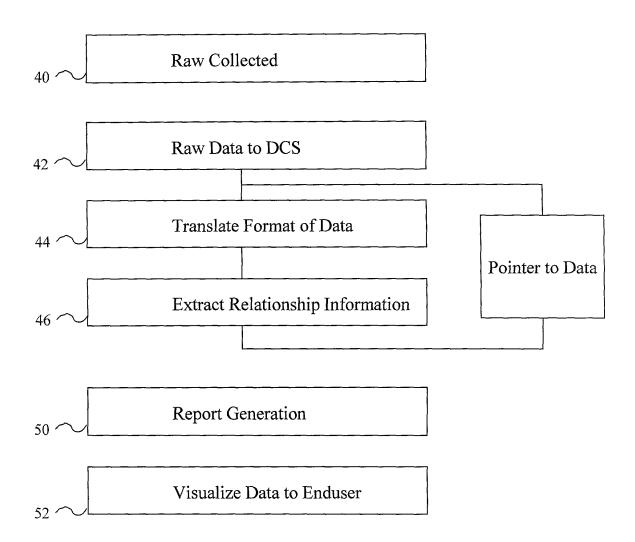
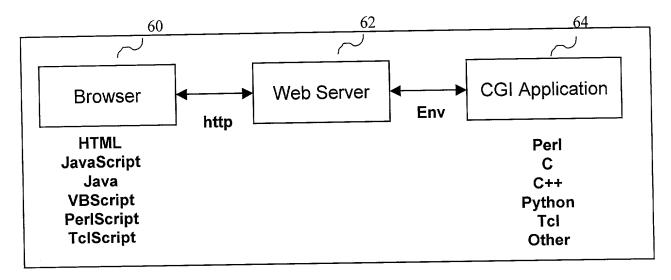


FIG.3

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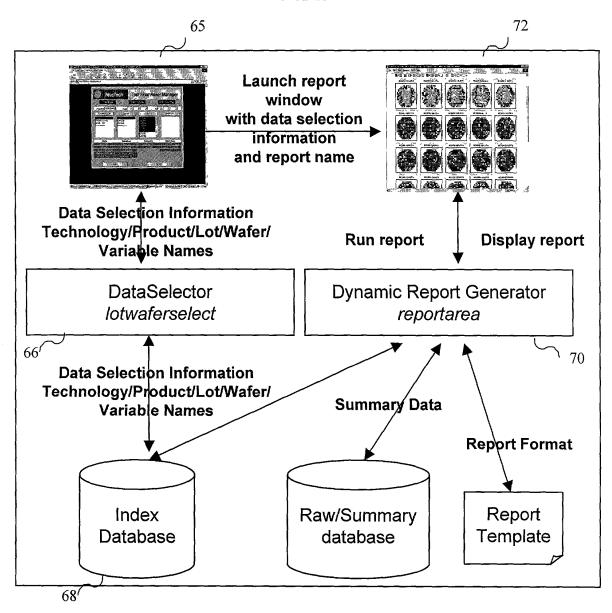


FIG.5

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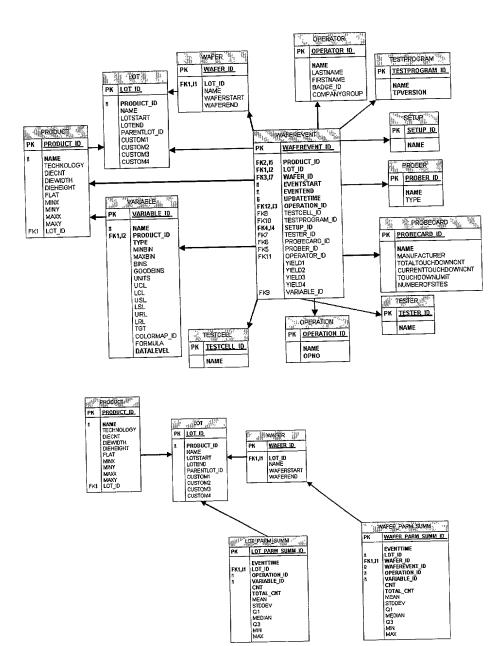


FIG.6

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Report Name	Report Description	Example
Lot Summary	A tabular reports that displays the lot bin summary for the selected lots. Click on an individual lot name to drill down to a Wafer Summary report	1
Lot Bin Histogram	Bar chart of bin count totals for selected lots.	The state of the s
Lot Yield Trend	Line trend chart of lot yields of the selected lots.	ASSOCIATE STORY THAT I SHOW THE FOREST CHAIR STORY THE S
Lot Yield Box Plot	Displays the distribution of wafer yields for the selected lots in a single report. The wafer yields are represented as a standard box plot.	Section 1997 1997 1997 1997 1997 1997 1997 199
Bin Summary	A tabular report that displays the wafer bin summary for the selected wafers. Click on an individual wafer name to drill down to a Bin Map report.	Absorber risk and the second of the second o
		From the case are seen were the case and the case of

FIG.7 (Sheet 1)

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Report Name	Report Description	Example
Wafer Bin Histogram	Bar chart of bin count totals for selected wafers.	Septiment of the second of the
Yield by Probe Card	Line trend chart of wafer yields of all selected wafers, sorted by probe card.	Pagastra variables and the second property of the second page of the s
Yield by Operator	Line trend chart of wafer yields of all selected wafers, sorted by operator.	State of the control
Wafer Test Times	A bar chart that plots the actual time taken to test a wafer and the associated yield trend line for that wafer.	No Image Available
Lot Test Times	A bar chart that plots the actual time taken to test a lot, and the associated yield trend line for that lot.	Table of the state

FIG.7 (Sheet 2)

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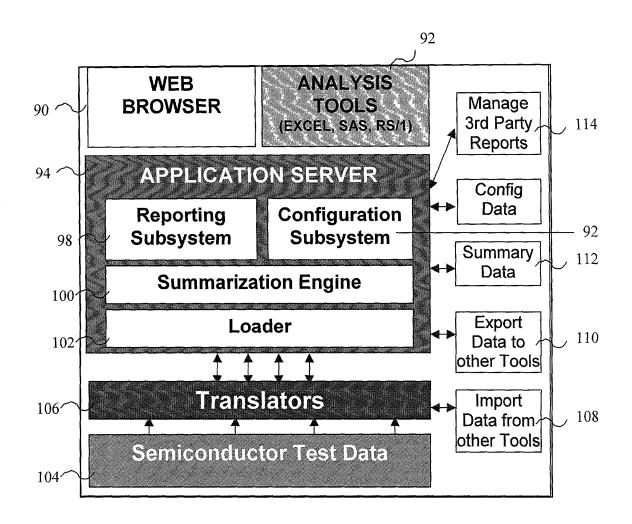
Report Name	Report Description	Example
Yield by Tester	Line trend chart of wafer yields of all selected wafers, sorted by tester.	No Image Available
86		
Yield by Prober	Line trend chart of wafer yields of all selected wafers, sorted by prober.	The state of the s
86		Semi-comparison and anti-many definition of the comparison of the
Parameter Gallery	Display a table of maps where each column is a parameter and each row is a wafer. Displays wafer maps for all parameters declared for the selected device. Click on an individual wafer map to zoom into that map. Use the browser "Back" button to return to the gallery.	The control of the co
Wafer Yield Trend	Line trend chart of wafer yields of the selected wafers.	Constitution of the consti
Bin Map	Displays a bin map of the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. FIG.7 (Sheet 3)	Table Say. Table

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Report Name	Report Description	Example
Pass/Fail Bin Map	Displays a pass/fail map for the selected wafers. This report uses the device configuration information to determine the pass bins. Displays maps for all wafers in the selected lots if no individual wafers are selected.	The state of the s
Bin Gallery	Displays a pass/fail map for the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. Click on an individual wafer map to zoom into that map.	
Percent Composite	Displays a composite yield map for the selected wafers. This report uses the device configuration information to determine the pass bins.	Secretary and the secretary an

FIG.7 (Sheet 4)

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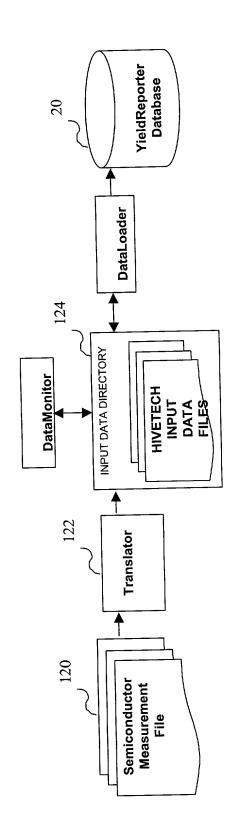
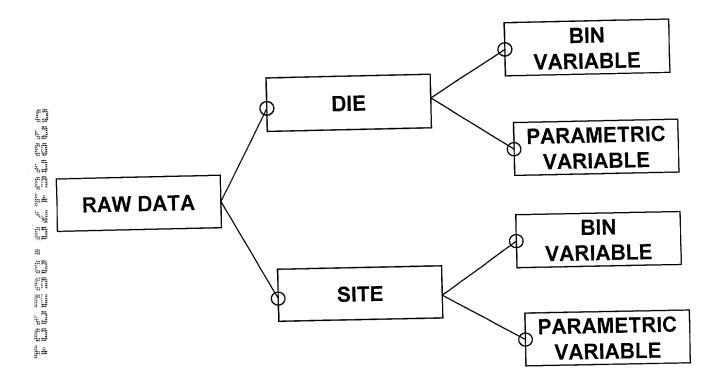
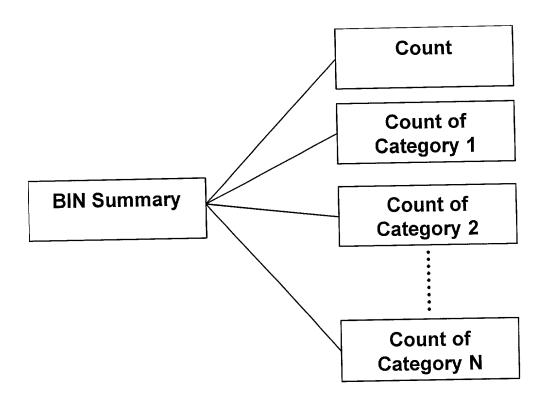


FIG.9



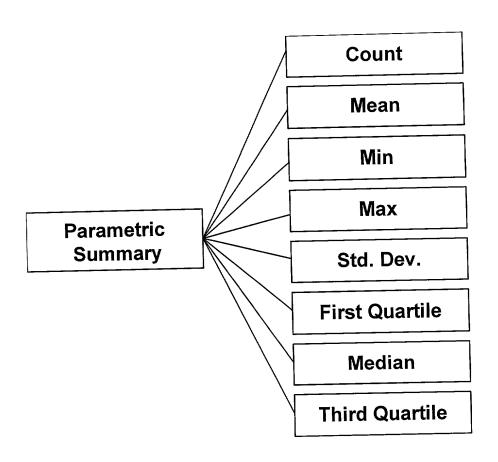
Variable Types

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Lot or Wafer Bin Summary

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Lot or Wafer Parametric Summary